

Notice of References Cited	Application/Control No. 10/028,629		Applicant(s)/Patent Under Reexamination CHAPMAN ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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X	B	US-6025851	02-2000	Valdes et al.	345/442
X	C	US-6441823	08-2002	Ananya	345/442
X	D	US-6111588	08-2000	Newell	345/442
X	E	US-5821414	10-1998	Noy et al.	73/152.54
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
X	U	"Derivation of a standard set of geometric constraints for parametric modeling and data exchange", Bettig et al., Computer-Aided Design 33 (2001) 17-33
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.